

STD35NF3LL

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STD35NF3LL	30V	<0.0195Ω	35A

- Optimal R_{DS}(on) x Q_q trade-off @ 4.5V
- Conduction losses reduced
- Switching losses reduced
- Low threshold drive

Description

This application specific Power MOSFET is the third generation of STMicroelectronics unique "single feature size™" strip-based process. The resulting transistor shows the best trade-off between on-resistance and gate charge. When used as high and low side in buck regulators, it gives the best performance in terms of both conduction and switching losses. This is extremely important for motherboards where fast switching and high efficiency are of paramount importance. remarkable manufacturing reproducibility.

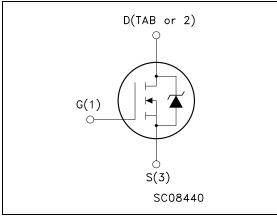
Applications

Switching application

Order codes

DPAK	

Internal schematic diagram



Part number	Marking	Package	Packaging
STD35NF3LLT4	D35NF3LL	DPAK	Tape & reel

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1 Electrical ratings

Table 1.	Absolute	maximum	ratings
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Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	30	V
V _{GS}	Gate- source voltage	± 16	V
I _D	Drain current (continuous) at $T_{C} = 25^{\circ}C$	35	Α
I _D	Drain current (continuous) at T _C = 100°C	25	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	140	Α
P _{tot}	Total dissipation at $T_{C} = 25^{\circ}C$	50	W
	Derating factor	0.33	W/°C
E _{AS} ⁽²⁾	Single pulse avalanche energy	300	mJ
T _{stg}	Storage temperature		•
Т _і	Max. operating junction temperature	-55 to 175	°C

1. Pulse width limited by safe operating area.

2. Starting $T_j = 25$ °C, $I_D = 17.5A$, $V_{DD} = 24V$

Table 2. Thermal data

Rthj-case	Thermal resistance junction-case max	3	°C/W
Rthj-amb	Thermal resistance junction-to ambient max	100	°C/W
TJ	T _J Maximum lead temperature for soldering purpose		°C



2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 250μA, V _{GS} =0	30			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = Max rating V _{DS} = Max rating @125°C			1 10	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	$V_{GS} = \pm 16V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1		2.5	V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10V, I_D = 17.5A$ $V_{GS} = 4.5V, I_D = 17.5A$		0.014 0.016	0.0195 0.0215	Ω Ω

Table 3. On/off states

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	V _{DS} = 15V, I _D = 17.5A		19		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25V, f = 1MHz, V _{GS} = 0		800 250 60		pF pF pF
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 15V, I_D = 17.5A$ $R_G = 4.7\Omega V_{GS} = 4.5V$ (see <i>Figure 12</i>)		17 100 20 21		ns ns ns ns
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$\label{eq:VDD} \begin{array}{l} V_{DD} = 24V, \ I_D = 35A, \\ V_{GS} = 5V, \ R_G = 4.7\Omega \\ (\text{see Figure 13}) \end{array}$		12.5 42 5.2	17	nC nC nC

1. Pulsed: Pulse duration = $300 \ \mu$ s, duty cycle 1.5%.

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Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)				35 140	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 35A, V _{GS} = 0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 35A, di/dt = 100A/μs, V _{DD} = 15V, T _j = 150°C (see <i>Figure 17</i>)		35 44 2.5		ns nC A

Table 5.Source drain diode

1. Pulse width limited by safe operating area.

2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%



2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

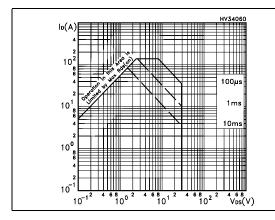
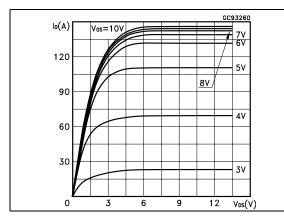


Figure 3. Output characteristics





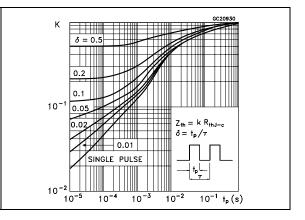


Figure 4. Transfer characteristics

Figure 2. Thermal impedance

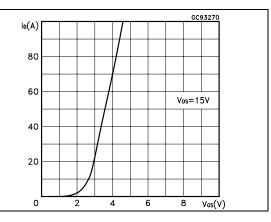
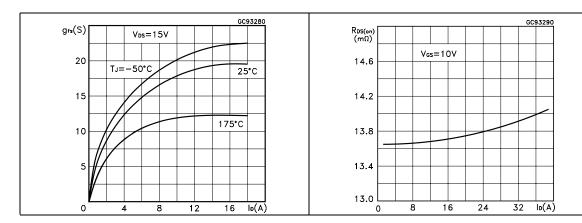


Figure 6. Static drain-source on resistance



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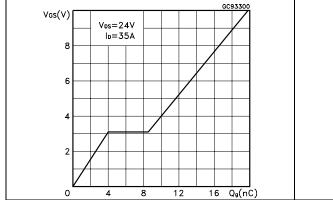


Figure 7. Gate charge vs. gate-source voltage Figure 8. Capacitance variations

Figure 9. Normalized gate threshold voltage vs. temperature

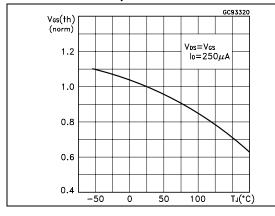
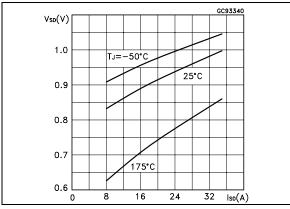


Figure 11. Source-drain diode forward characteristics



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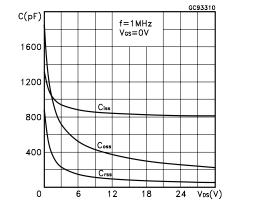
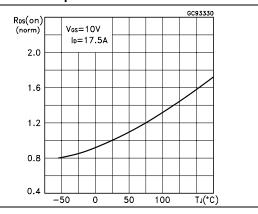


Figure 10. Normalized on resistance vs. temperature



3 Test circuit

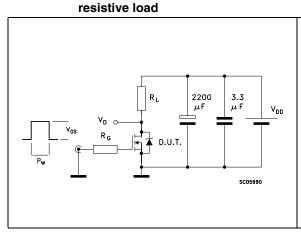
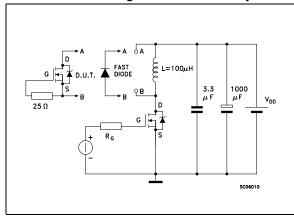


Figure 12. Switching times test circuit for

Figure 14. Test circuit for inductive load switching and diode recovery times



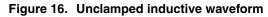


Figure 13. Gate charge test circuit

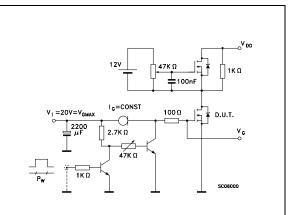


Figure 15. Unclamped Inductive load test circuit

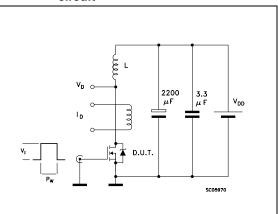
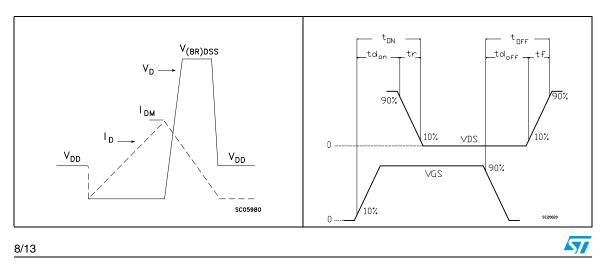


Figure 17. Switching time waveform



4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: *www.st.com*

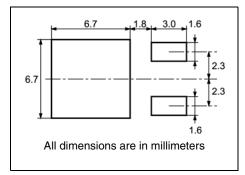


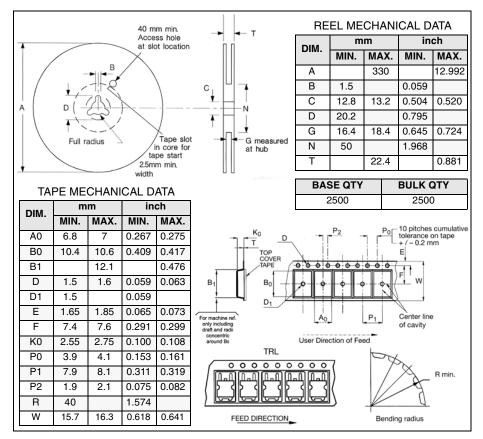
DIM. inc					inch	
DIN.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
E	6.4		6.6	0.252		0.260
E1	1	4.7			0.185	
е		2.28			0.090	
e1	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°
	ſ		c2		PAD	



5 Packing mechanical data

DPAK FOOTPRINT





TAPE AND REEL SHIPMENT

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6 Revision history

Table 6. Revision history

Date	Revision	Changes
21-Jun-2004	2	Preliminary version
06-Jul-2006	3	New template, no content change
14-sep-2006	4	Removed IPAK
20-Feb-2007	5	Typo mistake on page 1



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